

NTS3001 Bench Top Flash Memory Endurance Cycling System



- **1 Pattern Generator Zone**
- **Software Algorithmic Pattern Generator**
- **Windows Host Platform**
- **32 to 64 Device Capacity**
- **C++ Test Language**

NTS3000 SERIES APPLICATIONS

- Supports NOR, AND, NAND, serial and all Typical FLASH/NVM Device Architectures
- Determine Write/Erase Endurance Cycling
- Perform Sector Cycling
- Count Failed Bits During Cycling
- Measure Vt Levels and Shifts
- Generate Vt Histogram Plots
- Detect Cell Disturb Phenomenon
- DC Stress
- Flash Reliability Testing
- Qualify New Flash Device
- Qualify New Fabrication Process
- Qualify New Fabrication Plant
- Qualify New Package
- Optimize Flash Device Design
- Fabrication Plant Process Monitor
- Competitor Evaluation Tool